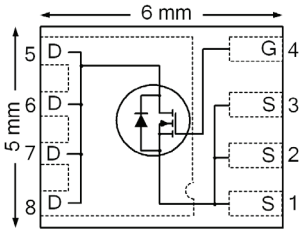
HEXFET® Power MOSFET

V_{DSS}	100	V
$R_{DS(on)}$ max (@ V_{GS} = 10V)	5.2	mΩ
$Q_{g\ (typical)}$	36	nC
$R_{g\ (typical)}$	1.2	Ω
I_D (@$T_{C\ (Bottom)}$ = 25°C)	123	A



PQFN 5X6 mm

Applications

- Primary Switch for High Frequency 48V/60V Telecom DC-DC Power Supplies
- Secondary Side Synchronous Rectifier
- Hot Swap and Active O-Ring

Features		Benefits
Low $R_{DS(ON)}$ (< 5.2mΩ)		Lower Conduction Losses
Low Thermal Resistance to PCB (<0.8°C/W)		Increased Power Density
100% Rg Tested		Increased Reliability
Low Profile (<1.05 mm)	results in	Increased Power Density
Industry-Standard Pinout	⇒	Multi-Vendor Compatibility
Compatible with Existing Surface Mount Techniques		Easier Manufacturing
RoHS Compliant, Halogen-Free		Environmentally Friendlier
MSL1		Increased Reliability

Base part number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
IRFH7185PbF	PQFN 5mm x 6 mm	Tape and Reel	4000	IRFH7185TRPbF

Absolute Maximum Ratings

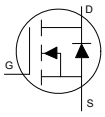
	Parameter	Max.	Units
V_{GS}	Gate-to-Source Voltage	± 20	V
I_D @ T_A = 25°C	Continuous Drain Current, V_{GS} @ 10V	19	A
I_D @ $T_{C(Bottom)}$ = 25°C	Continuous Drain Current, V_{GS} @ 10V	123	
I_D @ $T_{C(Bottom)}$ = 100°C	Continuous Drain Current, V_{GS} @ 10V	78	
I_{DM}	Pulsed Drain Current ①	260	
P_D @T_A = 25°C	Power Dissipation	3.6	W
P_D @$T_{C(Bottom)}$ = 25°C	Power Dissipation	160	
	Linear Derating Factor	0.03	W/°C
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to + 150	°C

Notes ① through ⑤ are on page 9

Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	100	—	—	V	V_{GS} = 0V, I_D = 250µA
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	54	—	mV/°C	Reference to 25°C, I_D = 1mA
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	4.2	5.2	mΩ	V_{GS} = 10V, I_D = 50A ③
$V_{GS(th)}$	Gate Threshold Voltage	2.0	—	3.6	V	V_{DS} = V_{GS}, I_D = 150µA
$\Delta V_{GS(th)}$	Gate Threshold Voltage Coefficient	—	-5.3	—	mV/°C	
I_{DSS}	Drain-to-Source Leakage Current	—	—	1.0	µA	V_{DS} = 80V, V_{GS} = 0V
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	V_{GS} = 20V
	Gate-to-Source Reverse Leakage	—	—	-100		V_{GS} = -20V
gfs	Forward Transconductance	117	—	—	S	V_{DS} = 25V, I_D = 50A
Q_g	Total Gate Charge	—	36	54	nC	V_{DS} = 50V V_{GS} = 10V I_D = 50A
Q_{gs1}	Pre-Vth Gate-to-Source Charge	—	7.3	—		
Q_{gs2}	Post-Vth Gate-to-Source Charge	—	2.7	—		
Q_{gd}	Gate-to-Drain Charge	—	11	—		
Q_{godr}	Gate Charge Overdrive	—	15	—		
Q_{sw}	Switch Charge (Q_{gs2} + Q_{gd})	—	13.7	—		
Q_{oss}	Output Charge	—	120	—	nC	V_{DS} = 50V, V_{GS} = 0V
R_G	Gate Resistance	—	1.2	—	Ω	
$t_{d(on)}$	Turn-On Delay Time	—	6.5	—	ns	V_{DD} = 50V, V_{GS} = 10V I_D = 50A R_G = 1.0Ω
t_r	Rise Time	—	9.9	—		
$t_{d(off)}$	Turn-Off Delay Time	—	14	—		
t_f	Fall Time	—	3.9	—		
C_{iss}	Input Capacitance	—	2320	—	pF	V_{GS} = 0V V_{DS} = 50V f = 1.0MHz
C_{oss}	Output Capacitance	—	1070	—		
C_{rss}	Reverse Transfer Capacitance	—	19	—		

Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	123	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	260		
V_{SD}	Diode Forward Voltage	—	0.8	1.3	V	T_J = 25°C, I_S= 50A, V_{GS}=0V ③
t_{rr}	Reverse Recovery Time	—	63	95	ns	T_J = 25°C, I_F = 50A, V_{DD} = 50V
Q_{rr}	Reverse Recovery Charge	—	110	165	nC	di/dt = 100A/µs ③

Avalanche Characteristics

	Parameter	Typ.	Max.	Units
E_{AS}	Single Pulse Avalanche Energy ②	—	360	mJ
I_{AR}	Avalanche Current ①	—	50	A

Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$ (Bottom)	Junction-to-Case ④	—	0.8	°C/W
$R_{\theta JC}$ (Top)	Junction-to-Case ④	—	19	
$R_{\theta JA}$	Junction-to-Ambient ⑤	—	35	
$R_{\theta JA}$ (<10s)	Junction-to-Ambient ⑤	—	23	

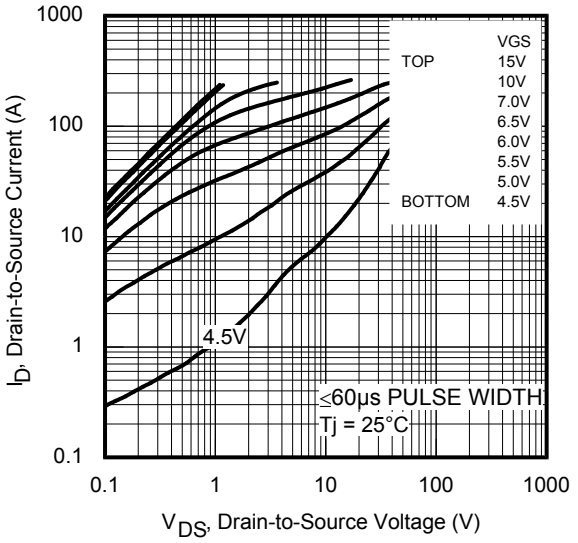


Fig 1. Typical Output Characteristics

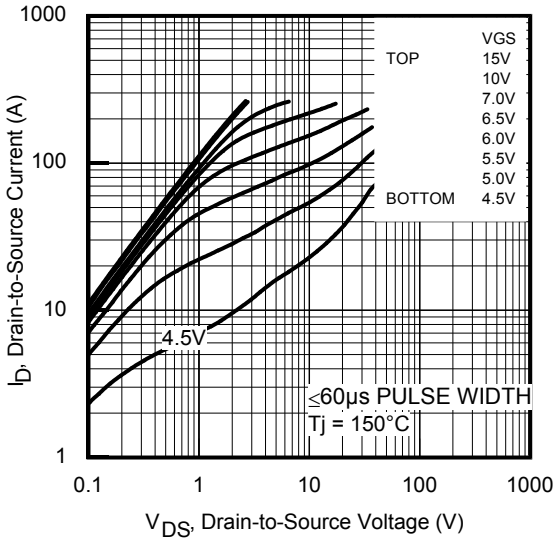


Fig 2. Typical Output Characteristics

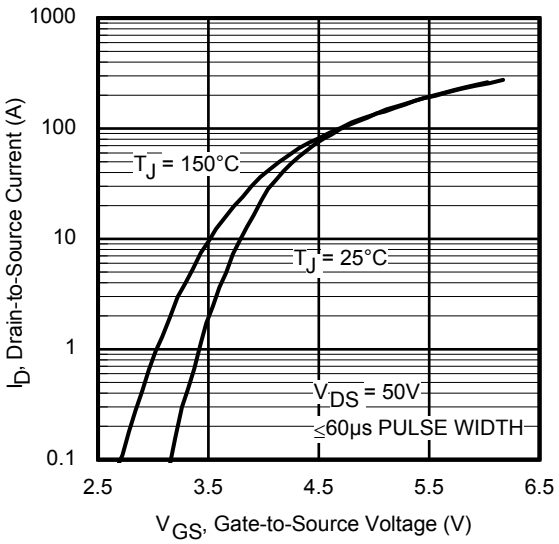


Fig 3. Typical Transfer Characteristics

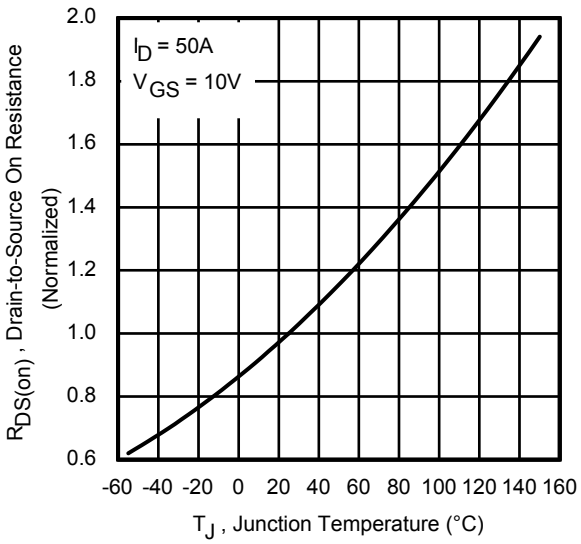


Fig 4. Normalized On-Resistance vs. Temperature

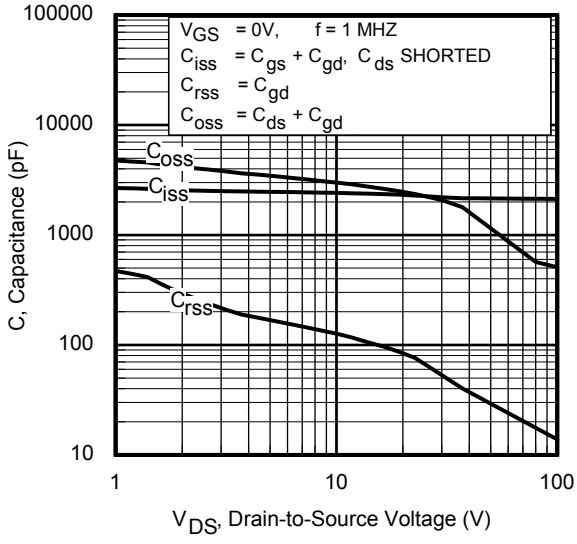


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

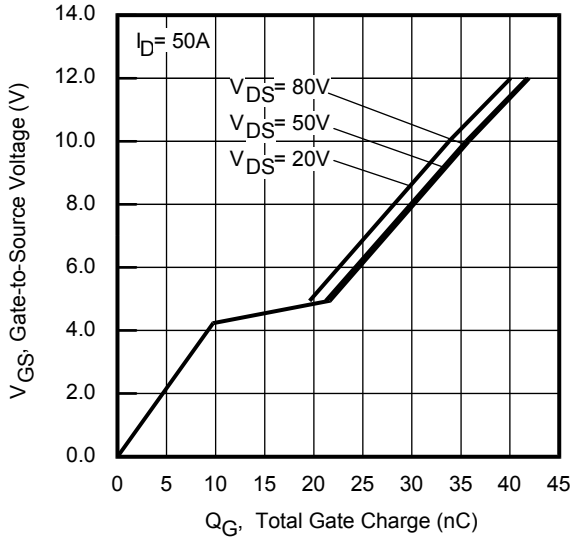


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

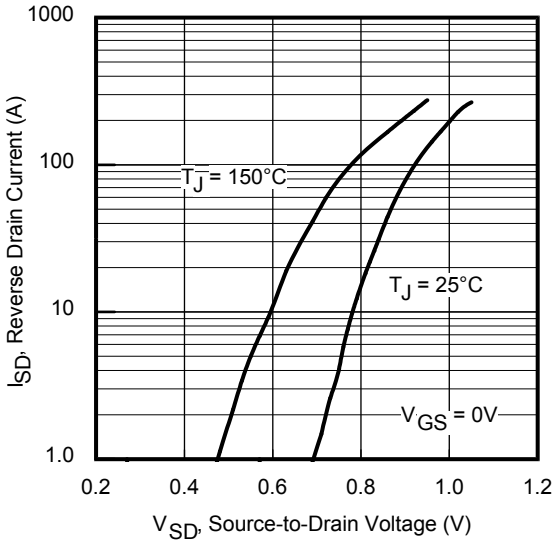


Fig 7. Typical Source-Drain Diode Forward Voltage

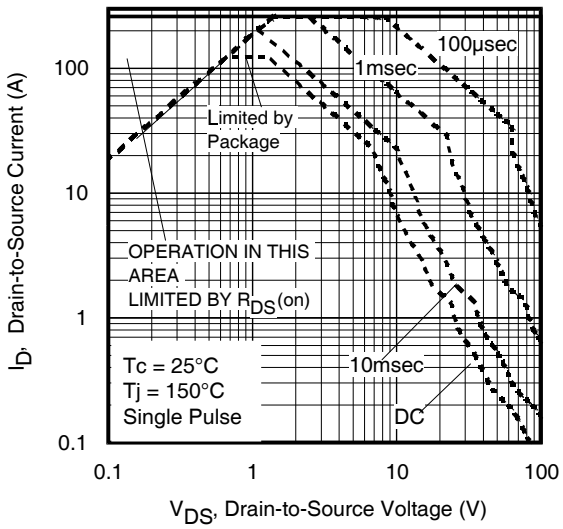


Fig 8. Maximum Safe Operating Area

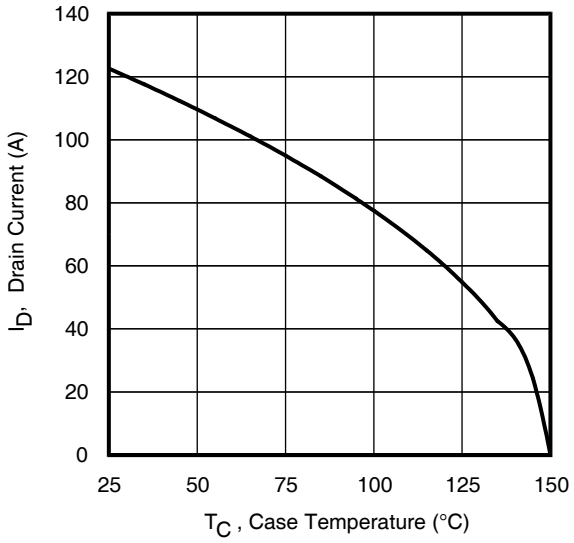


Fig 9. Maximum Drain Current vs. Case Temperature

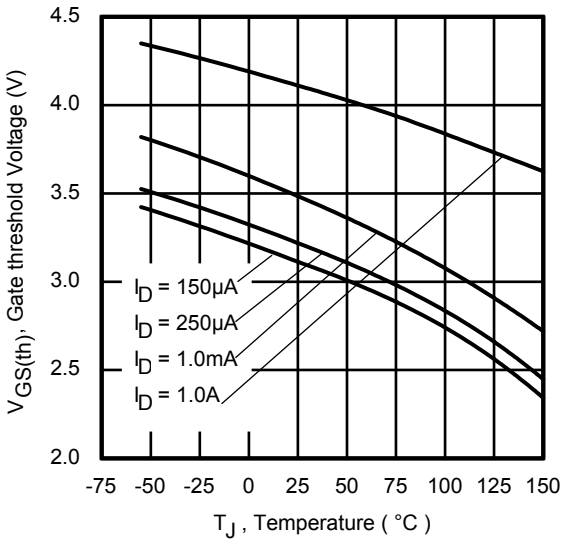


Fig 10. Threshold Voltage vs. Temperature

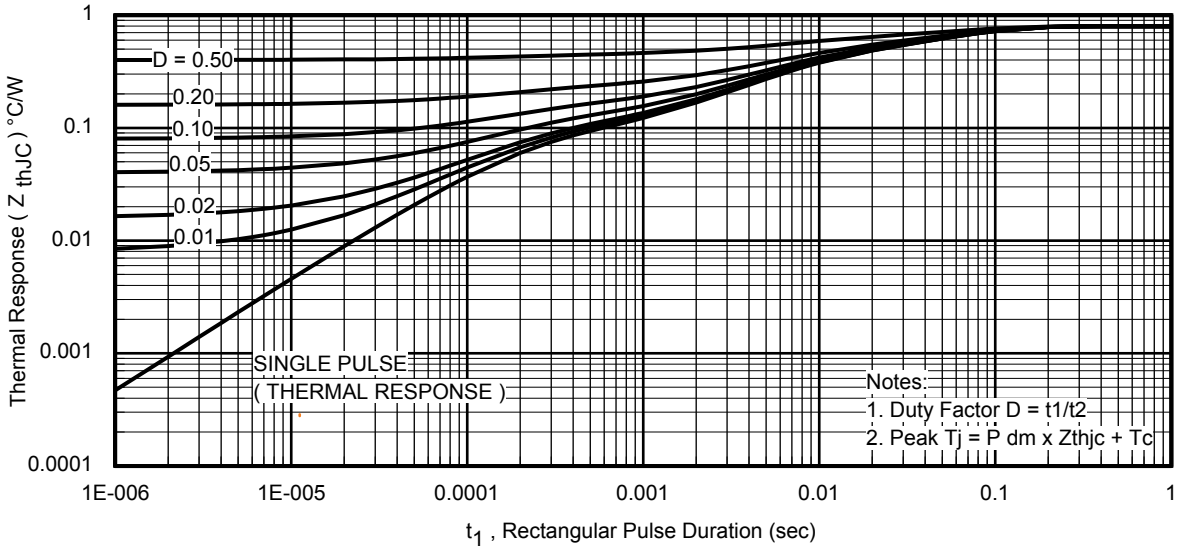


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

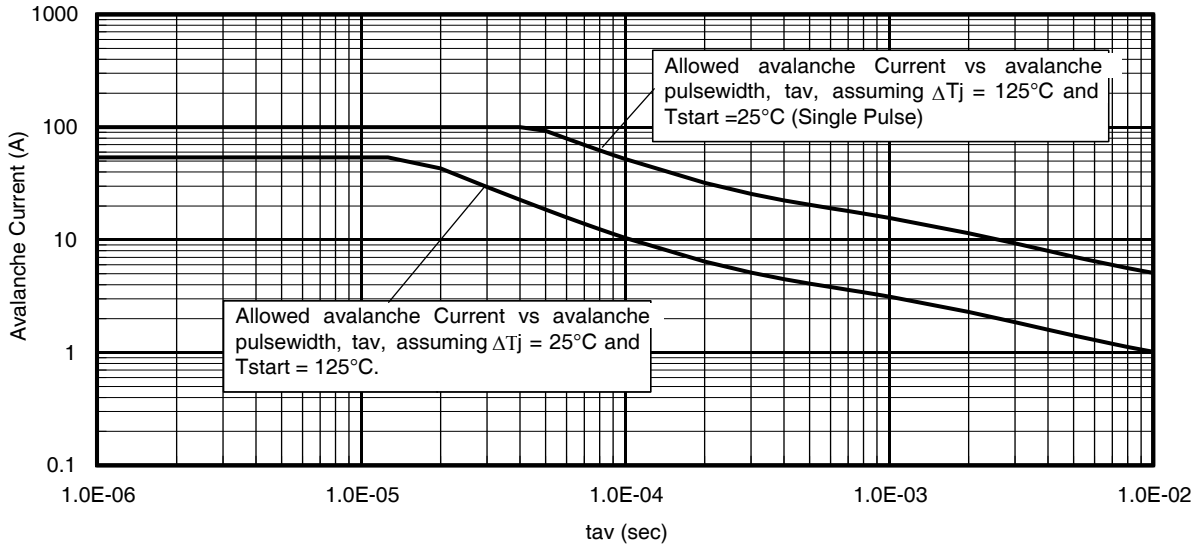


Fig 12. Typical Avalanche Current vs. Pulse Width

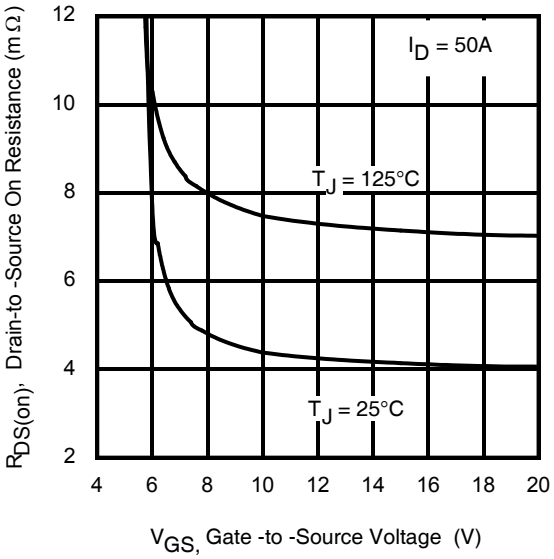


Fig 13. On–Resistance vs. Gate Voltage

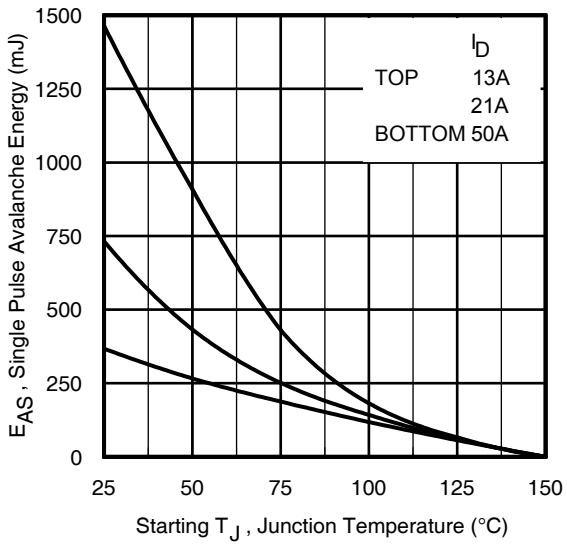


Fig 14. Maximum Avalanche Energy vs. Drain Current

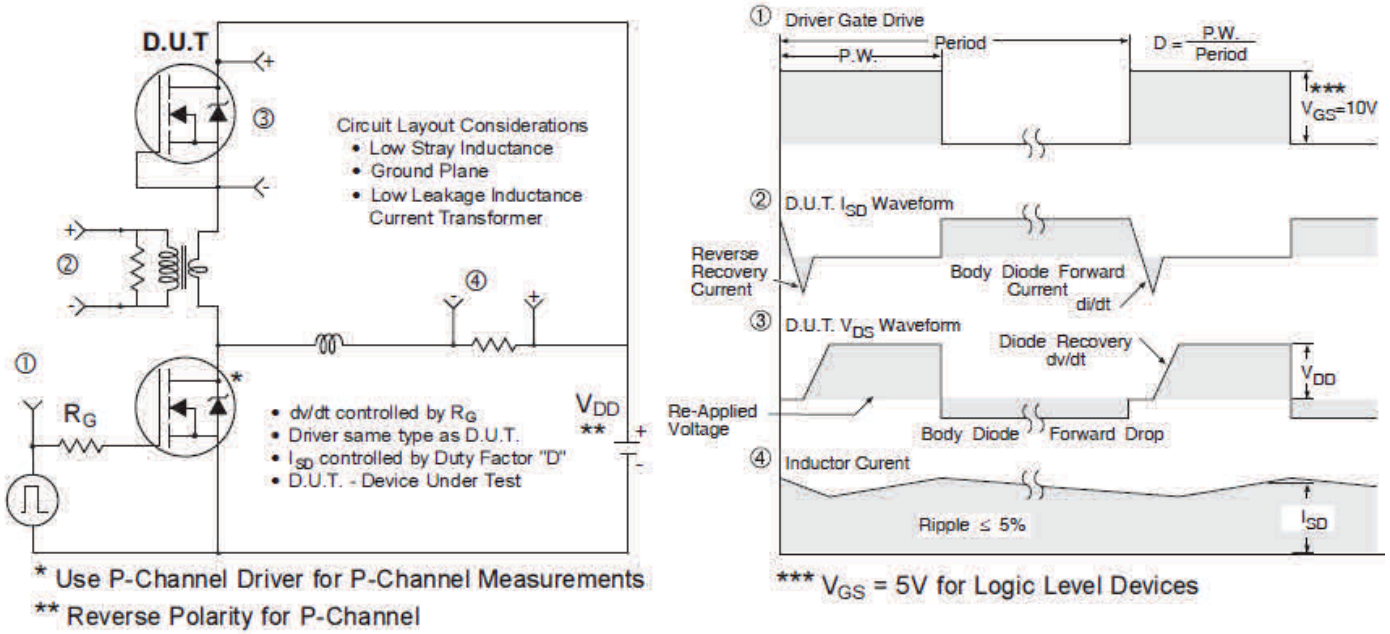


Fig 15. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

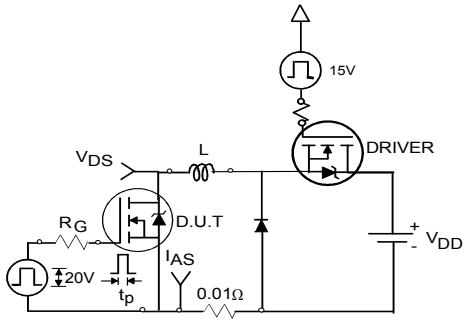


Fig 16a. Unclamped Inductive Test Circuit

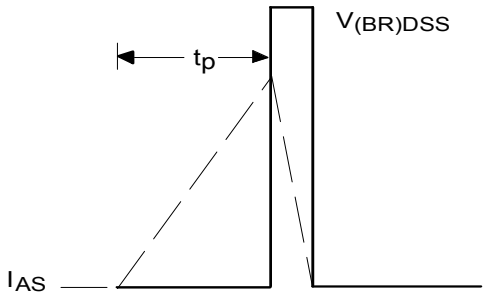


Fig 16b. Unclamped Inductive Waveforms

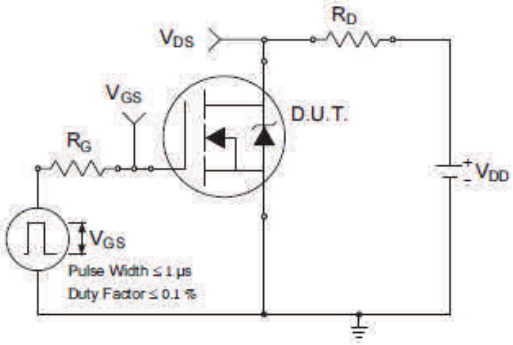


Fig 17a. Switching Time Test Circuit

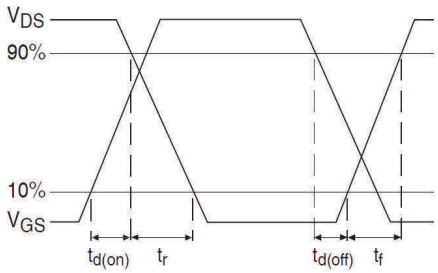


Fig 17b. Switching Time Waveforms

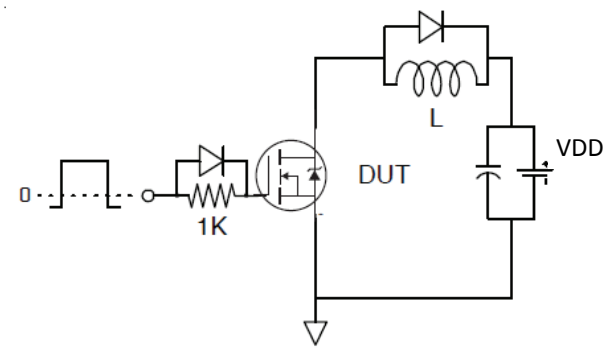


Fig 18. Gate Charge Test Circuit

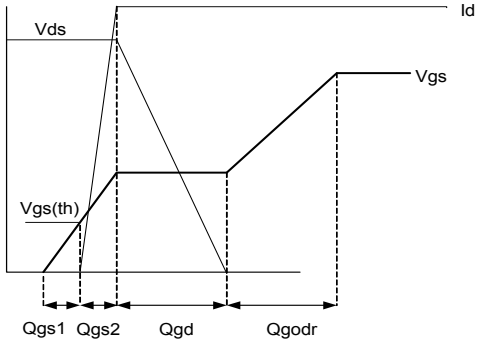
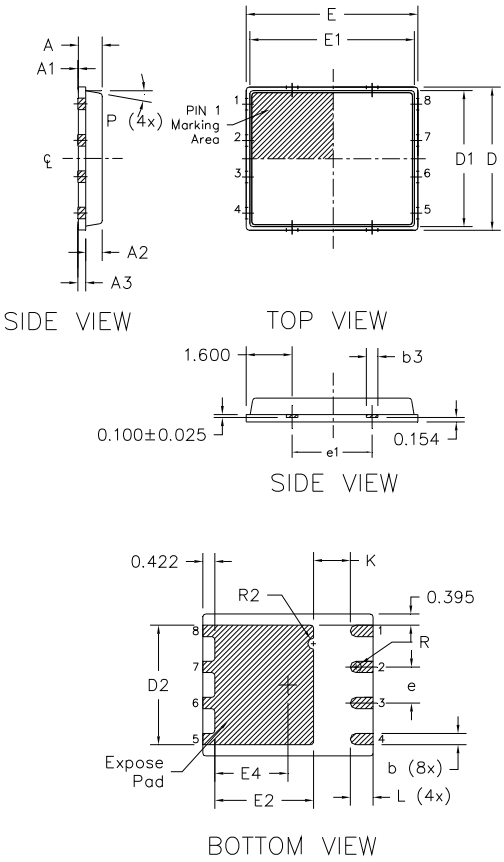


Fig 19. Gate Charge Waveform

PQFN 5x6 Outline "B" Package Details



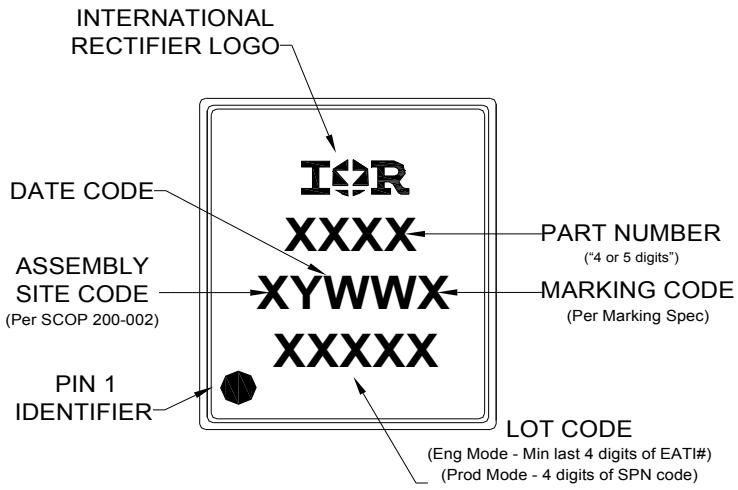
DIM / SYMBOL	MILLIMITERS MIN	MILLIMITERS MAX	INCH MIN	INCH MAX
A	0.800	0.900	0.0315	0.0543
A1	0.000	0.050	0.0000	0.0020
A3	0.200 REF		0.0079 REF	
b	0.350	0.470	0.0138	0.0185
b1	0.025	0.125	0.0010	0.0049
b2	0.210	0.410	0.0083	0.0161
b3	0.150	0.450	0.0059	0.0177
D	5.000 BSC		0.1969 BSC	
D1	4.750 BSC		0.1870 BSC	
D2	4.100	4.300	0.1614	0.1693
E	6.000 BSC		0.2362 BSC	
E1	5.750 BSC		0.2264 BSC	
E2	3.380	3.780	0.1331	0.1488
e	1.270 REF		0.0500 REF	
e1	2.800 REF		0.1102 REF	
K	1.200	1.420	0.0472	0.0559
L	0.710	0.900	0.0280	0.0354
P	0°	12°	0°	12°
R	0.200 REF		0.0079 REF	
R2	0.150	0.200	0.0059	0.0079

Note:

1. Dimensions and tolerancing confirm to ASME Y14.5M–1994
2. Dimension L represents terminal full back from package edge up to 0.1mm is acceptable
3. Coplanarity applies to the expose Heat Slug as well as the terminal
4. Radius on terminal is Optional

For more information on board mounting, including footprint and stencil recommendation, please refer to application note AN-1136: http://www.irf.com/technical-info/appnotes/an-1136.pdf
For more information on package inspection techniques, please refer to application note AN-1154: http://www.irf.com/technical-info/appnotes/an-1154.pdf

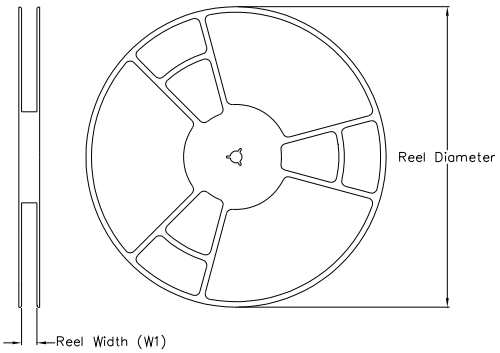
PQFN 5x6 Part Marking



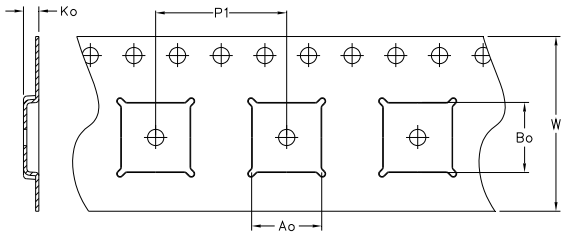
Note: For the most cur- rent drawing

PQFN 5x6 Tape and Reel

REEL DIMENSIONS

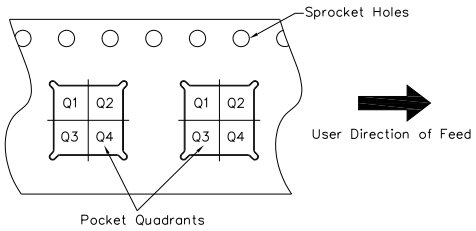


TAPE DIMENSIONS



CODE	DESCRIPTION
Ao	Dimension design to accommodate the component width
Bo	Dimension design to accommodate the component lenght
Ko	Dimension design to accommodate the component thickness
W	Overall width of the carrier tape
P_1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



Note: All dimension are nominal

Package Type	Reel Diameter (Inch)	QTY	Reel Width W1 (mm)	Ao (mm)	Bo (mm)	Ko (mm)	P1 (mm)	W (mm)	Pin 1 Quadrant
5 X 6 PQFN	13	4000	12.4	6.300	5.300	1.20	8.00	12	Q1

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

Qualifiction Information†

Qualification Level	Industrial (per JEDEC JESD47F†† guidelines)	
Moisture Sensitivity Level	PQFN 5mm x 6mm	MSL1 (per JEDEC J-STD-020D††)
RoHS Compliant	Yes	

† Qualification standards can be found at International Rectifier's web site: http://www.irf.com/product-info/reliability/

†† Applicable version of JEDEC standard at the time of product release.

Notes:

① Repetitive rating; pulse width limited by max. junction temperature.
② Starting T_J = 25°C, L = 290µH, R_G = 50Ω, I_{AS} = 50A.
③ Pulse width ≤ 400µs; duty cycle ≤ 2%.
④ R_θ is measured at T_J of approximately 90°C.
⑤ When mounted on 1 inch square PCB (FR-4). Please refer to AN-994 for more details: http://www.irf.com/technical-info/appnotes/an-994.pdf

Revision History

Date	Comments
3/13/2014	• Updated the EAS specification on pages 2 & 8. • Updated the Zth data used on figure 11, page 4. • Updated figures 8, 11, 12, & 14 on pages 4 & 5.
6/26/2014	• Update package limit current to 123A and Fig.8 & 9 on page 4
09/25/2014	• Corrected Min Gfs from 280S to 117S on page 2 • Updated PQFN 5 x6 Outline "B" Tape and Reel on page 8
10/20/2014	• Typo error—Deleted Note # 6 from page 1 and Diode Characteristic Table on page 2
3/17/2015	• Updated package outline on pages 7.

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To contact International Rectifier, please visit http://www.irf.com/whoto-call/

